


<b>Search Notes</b>  	<b>Application/Control No.</b>  10045929	<b>Applicant(s)/Patent Under Reexamination</b>  LIN ET AL.
	<b>Examiner</b>  M. Lee	<b>Art Unit</b>  2622

SEARCHED			
Class	Subclass	Date	Examiner
348	571, 715-718, 561, 537 , 581, 596,	2/11/10	ml
715	788, 789	2/11/10	ml
341	122	2/11/10	ml

SEARCH NOTES		
Search Notes	Date	Examiner
east	2/11/10	ml

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
	Interference search history result attached.	2/11/10	ml

	/M. Lee/ Primary Examiner.Art Unit 2622
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